MOSFET - N-Channel, SUPERFET III, FRFET

650 V, 24 A, 150 mΩ

Description

SUPERFET III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate.

Consequently, SUPERFET III MOSFET is very suitable for the various power systems for miniaturization and higher efficiency. SUPERFET III FRFET MOSFET's optimized reverse recovery performance of body diode can remove additional component and improve system reliability.

Features

- $700 \text{ V} @ \text{T}_{\text{I}} = 150^{\circ}\text{C}$
- Typ. $R_{DS(on)} = 121 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. Q_g = 43 nC)
- Low Effective Output Capacitance (Typ. Coss(eff.) = 400 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

Applications

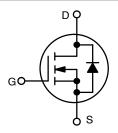
- Telecom / Server Power Supplies
- Industrial Power Supplies
- EV Charger
- UPS / Solar



ON Semiconductor®

www.onsemi.com

V _{DSS}	R _{DS(ON)} MAX	I _D MAX
650 V	150 mΩ @ 10 V	24 A



N-CHANNEL MOSFET



D²PAK (TO-263 3-Lead) CASE 418AJ

MARKING DIAGRAM

\$Y&Z&3&K NTB150 N65S3HF

\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = Data Code (Year & Week)

&K = Lot

NTB150N65S3HF = Specific Device Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

ABSOLUTE MAXIMUM RATINGS ($T_C = 25^{\circ}C$, Unless otherwise noted)

Symbol	Parameter	Value	Unit	
V_{DSS}	Drain to Source Voltage		650	V
V_{GSS}	Gate to Source Voltage	- DC	±30	V
		- AC (f > 1 Hz)	±30	
I _D	Drain Current	– Continuous (T _C = 25°C)	24	А
		– Continuous (T _C = 100°C)	15.2	
I _{DM}	Drain Current	- Pulsed (Note 1)	60	Α
E _{AS}	Single Pulsed Avalanche Energy (Note 2)	275	mJ	
I _{AS}	Avalanche Current (Note 2)		3.8	Α
E _{AR}	Repetitive Avalanche Energy (Note 1)		1.92	mJ
dv/dt	MOSFET dv/dt		100	V/ns
	Peak Diode Recovery dv/dt (Note 3)	50	1	
P_{D}	Power Dissipation	(T _C = 25°C)	192	W
		- Derate Above 25°C	1.54	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
TL	Maximum Lead Temperature for Soldering, 1/8"	300	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Repetitive rating: pulse–width limited by maximum junction temperature.
 2. $I_{AS}=3.8$ A, $R_{G}=25$ Ω , starting $T_{J}=25^{\circ}C$.
 3. $I_{SD}\leq 12$ A, di/dt ≤ 200 A/ μ s, $V_{DD}\leq 400$ V, starting $T_{J}=25^{\circ}C$.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case, Max.	0.65	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient, Max., (Note 4)	40	

^{4.} Device on 1 in² 2-oz copper pad on 1.5 x 1.5 in. board of FR-4 material.

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Reel Size	Tape Width	Shipping [†]
NTB150N65S3HF	NTB150N65S3HF	D ² PAK	330 mm	24 mm	800 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
OFF CHARACT	ERISTICS	•	-	-	<u>-</u>	<u> </u>
BV _{DSS}	Drain to Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 25^{\circ}\text{C}$	650			V
		V _{GS} = 0 V, I _D = 1 mA, T _J = 150°C	700			V
$\Delta \text{BV}_{\text{DSS}} / \Delta \text{T}_{\text{J}}$	Breakdown Voltage Temperature Coefficient	I _D = 15 mA, Referenced to 25°C		0.62		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 650 V, V _{GS} = 0 V			10	μΑ
		V _{DS} = 520 V, T _C = 125°C		67		
I _{GSS}	Gate to Body Leakage Current	V _{GS} = ±30 V, V _{DS} = 0 V			±100	nA
ON CHARACTE	RISTICS				-	
V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 0.54 \text{ mA}$	3.0		5.0	V
R _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 12 A		121	150	mΩ
9FS	Forward Transconductance	V _{DS} = 20 V, I _D = 12 A		14		S
DYNAMIC CHAI	RACTERISTICS				-	
C _{iss}	Input Capacitance			1985		pF
C _{oss}	Output Capacitance	$V_{DS} = 400 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		40		pF
C _{oss(eff.)}	Effective Output Capacitance	V _{DS} = 0 V to 400 V, V _{GS} = 0 V		400		pF
C _{oss(er.)}	Energy Related Output Capacitance	V _{DS} = 0 V to 400 V, V _{GS} = 0 V		71		pF
Q _{g(tot)}	Total Gate Charge at 10 V			43		nC
Q_{gs}	Gate to Source Gate Charge	V _{DS} = 400 V, I _D = 12 A, V _{GS} = 10 V (Note 5)		13		nC
Q_{gd}	Gate to Drain "Miller" Charge	(1010 0)		17		nC
ESR	Equivalent Series Resistance	f = 1 MHz		5.0		Ω
SWITCHING CH	IARACTERISTICS					
t _{d(on)}	Turn-On Delay Time			21		ns
t _r	Turn-On Rise Time	V _{DD} = 400 V, I _D = 12 A, V _{GS} = 10 V		19		ns
t _{d(off)}	Turn-Off Delay Time	$R_g = 4.7 \Omega$ (Note 5)		63		ns
t _f	Turn-Off Fall Time	1		14		ns
SOURCE-DRAII	N DIODE CHARACTERISTICS				•	
I _S	Maximum Continuous Source to Drain Diode Forward Current				24	Α
I _{SM}	Maximum Pulsed Source to Drain Diode Forward Current				60	Α
V _{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 12 A			1.3	V
t _{rr}	Reverse Recovery Time	V _{DD} = 400 V, I _{SD} = 12 A,		88		ns
Q _{rr}	Reverse Recovery Charge	dl _F /dt = 100 A/μs		306		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Essentially independent of operating temperature typical characteristics.

TYPICAL CHARACTERISTICS

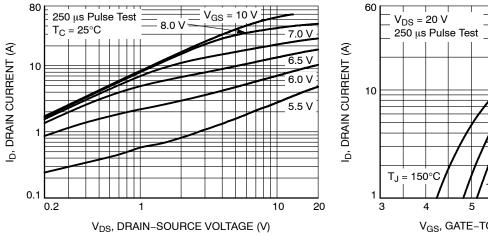


Figure 1. On-Region Characteristics

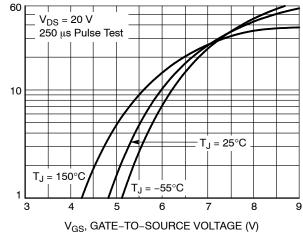


Figure 2. Transfer Characteristics

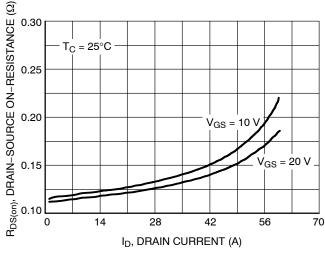


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

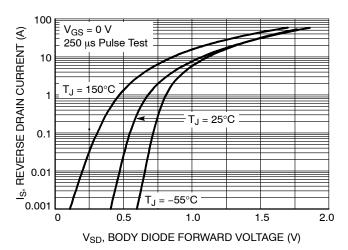


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

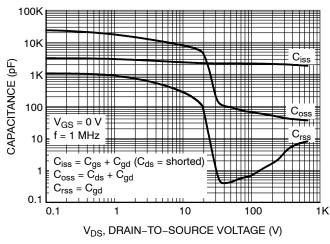


Figure 5. Capacitance Characteristics

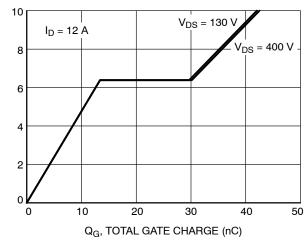


Figure 6. Gate Charge Characteristics

V_{GS}, GATE-SOURCE VOLTAGE (V)

TYPICAL CHARACTERISTICS

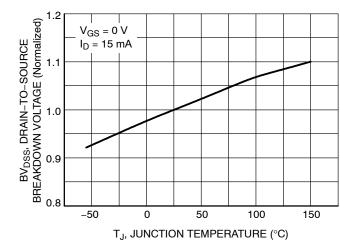
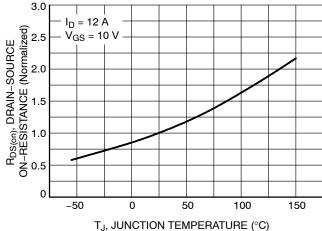


Figure 7. Breakdown Voltage Variation vs. Temperature



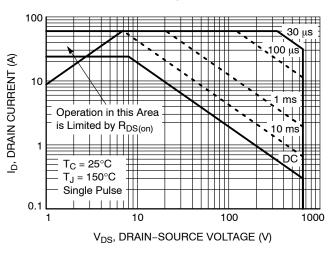
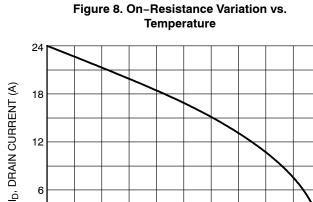


Figure 9. Maximum Safe Operating Area



T_C, CASE TEMPERATURE (°C)

100

125

150

75

25

50

Figure 10. Maximum Drain Current vs. Case **Temperature**

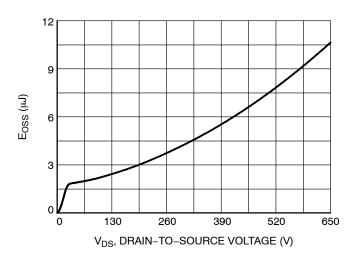


Figure 11. E_{OSS} vs. Drain-to-Source Voltage

TYPICAL CHARACTERISTICS

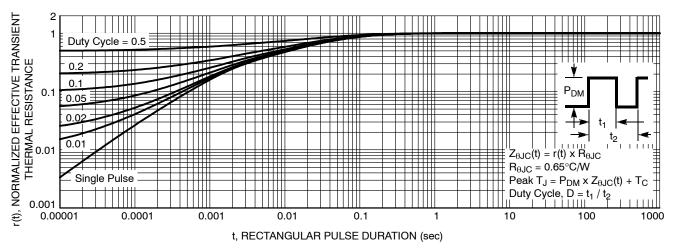


Figure 12. Transient Thermal Response Curve

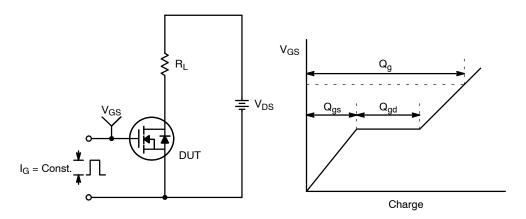


Figure 13. Gate Charge Test Circuit & Waveform

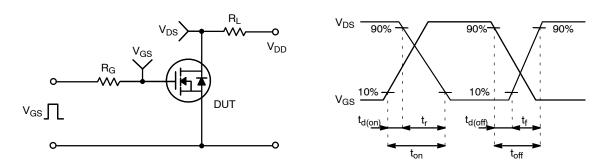


Figure 14. Resistive Switching Test Circuit & Waveforms

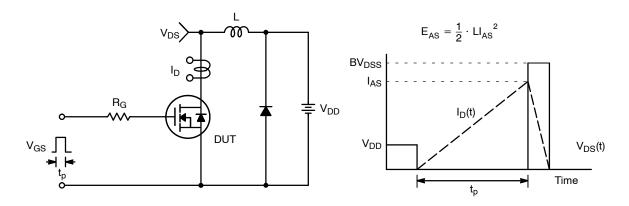


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

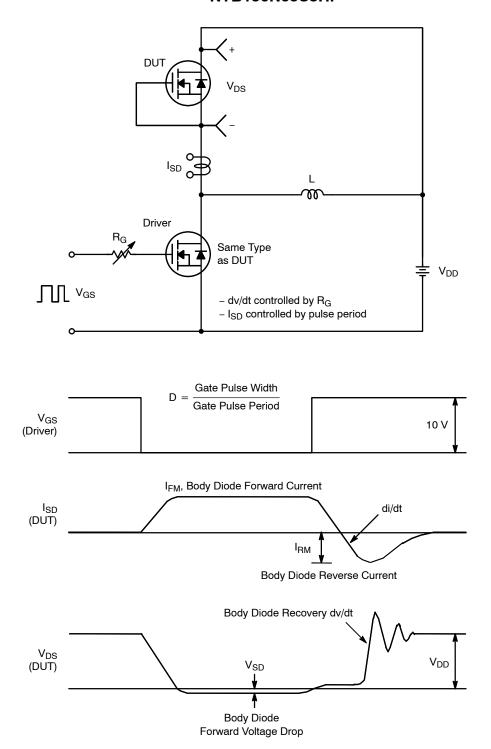
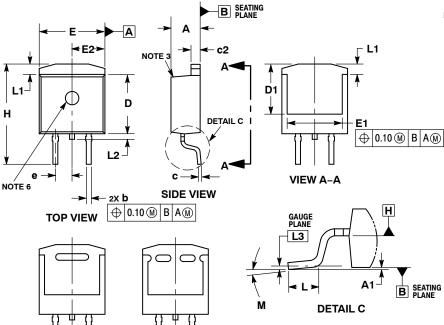


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms

PACKAGE DIMENSIONS

D²PAK-3 (TO-263, 3-LEAD) CASE 418AJ **ISSUE B**



VIEW A-A OPTIONAL CONSTRUCTIONS

NOTES:

- NOTES:

 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

 2. CONTROLLING DIMENSION: INCHES.

 3. CHAMFER OPTIONAL

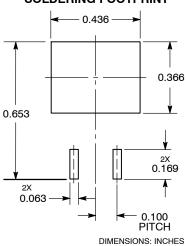
 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.005 PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
- TIC BODY AT DATUM H.

 5. THERMAL PAD CONTOUR IS OPTIONAL WITHIN DIMENSIONS E, L1, D1 AND E1.

 6. OPTIONAL MOLD FEATURE

	INCHES		MILLIN	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.160	0.190	4.06	4.83	
A1	0.000	0.010	0.00	0.25	
b	0.020	0.039	0.51	0.99	
С	0.012	0.029	0.30	0.74	
c2	0.045	0.065	1.14	1.65	
D	0.330	0.380	8.38	9.65	
D1	0.260		6.60		
E	0.380	0.420	9.65	10.67	
E1	0.245		6.22		
е	0.100	BSC 2.5		4 BSC	
Н	0.575	0.625	14.60	15.88	
L	0.070	0.110	1.78	2.79	
L1		0.066		1.68	
L2		0.070		1.78	
L3	0.010	BSC	0.25 BSC		
М	٥°	8°	٥°	8°	

RECOMMENDED SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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